

## **Delhi Technological University**

(Formerly Delhi College of Engineering) Shahbad Daulatpur, Bawana Road, Delhi – 110 042, India

Consequent upon the evaluation of the thesis submitted by the candidate(s) as per details given below for the award of Doctor of Philosophy (Ph.D.) of the Delhi Technological University on the topic as mentioned against his/her name and after his/her viva-voce examinations, he/she/they has/have been found qualified for the Award of Degree of Doctor of Philosophy (Ph.D.) of the University.

## **Department of Computer Engineering**

S.No.	Roll. No.	Name of Student	Name of	Date of Viva –
			Student	voice
			(In Hindi)	examination
1.	2K14/PHDCO/03	ASHISH KUMAR TRIPATHI	आशीष कुमार त्रिपाठी	10 <sup>th</sup> May, 2019
Title of Ph.D. Thesis		Big Data Analysis Using Metaheuristic Algorithms	बिग डाटा एनालाइसेस यूजिंग मेटाहियूरिस्टिक एल्गोरिदिमस	

**In-charge (Results)** 

(Controller of Examinations)

Dated: 30<sup>th</sup> May, 2019



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## **Department of Electrical Engineering**

S.No.	Roll. No.	Name of Student	Name of Student (In Hindi)	Date of Viva – voice examination
1.	2K16/PHDEE/05	AJAY KUMAR	अजय कुमार	22 <sup>nd</sup> May, 2019
Title of Ph.D. Thesis		"Analytical Modeling and TCAD Simulation of IN₂O₅SN Transparent Gate Electrode Recessed Channel MOSFET for High Performance Applications"	"एनालिटिकल मॉडिलें ग एण्ड TCAD सिमुलेशन ऑफ In₂O₅Sn ट्रान्सपेरेन्ट गेट इलेक्ट्रोड रिसेस्ड चैनल MOSFET फॉर हाई परफॉरमेन्स एप्लिकेशनस्"	

**In-charge (Results)** 

(Controller of Examinations)

Dated: 30<sup>th</sup> May, 2019